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App #: 10-807187

EAST SEARCH HISTORY

Databases: US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB

Ref#	Hits	Search Text
· S2	2	(("6,538,249") or ("6,456,899")).PN.
S3	1032	((determin\$2 or find\$3 or detect\$3) near (\$3focus\$3)) and image and (semiconductor or wafer) and correlation
S4	208	S3 and ((determin\$2 or find\$3 or detect\$3) near (edge))
S5	92	S4 and @pd<"20040324"
S6	92	S5 and (distances or depths or heights)
S7	13	("3829691" "4698503" "4733074" "4894540" "4941980" "5130540" "5142147" "5512747" "5523568" "5608218" "6067164" "6172365" "6278114").PN.
S8	7	S7 and edge
S9	6	S8 and predetermined
S10	6	("5544256" "5943437" "6259960" "6288782" "6292582" "6314379").PN.
S11	1	10/807187
S12	676	\$3 focus\$3 and image and (semiconductor or wafer) and correlation and edge and "electron microscope" and (wafer or semiconductor) and (distances or depths or heights)
S13	151	S12 and ((determin\$2 or find\$3 or detect\$3) near (edge))
S14	68	S13 and @pd<"20040324"
S15	40	S14 and defects
S16	29	S15 and predetermined
S17	74	("4111557" "4247203" "4333838" "4347001" "4448532" "4455485" "4532650" "4549204" "4555798" "4556317" "4579455" "4604910" "4618938" "4633504" "4639587" "4644172" "4758094" "4786170" "4805123" "4818110" "4845373" "4845558" "4877326" "4926489" "4957367" "5030008" "5032735" "5112129" "5129010" "5243406" "5280542" "5355212" "5438413" "5438417" "5448364" "5465145" "5502306" "5537669" "5563702" "5572598" "5578821" "5583632" "5621532" "5627646" "5671056" "5680207" "H001530" "Re34214").PN. OR ("5923430").URPN.
S18	34	S17 and edge
S19	27	S18 and defect
S20	1	((determin\$2 or find\$3 or detect\$3) near ("in focus")) and (distances or depths or heights) and edge and predetermined and image and (semiconductor or wafer) and "electron microscope"
S21	1	((determin\$2 or find\$3 or detect\$3) near ("in focus")) and (distances or depths or heights) and edge and image and (semiconductor or wafer) and "electron microscope"
S22	48	((determin\$2 or find\$3 or detect\$3) near ("in focus")) and (distances or depths or heights) and edge and image and (semiconductor or wafer)
S23	7	((determin\$2 or find\$3 or detect\$3) near ("in focus")) and (distances or depths or heights) and edge and image and (semiconductor or wafer) and defect
S24	24	((determin\$2 or find\$3 or detect\$3) near ("in-focus")) and (distances or depths or heights) and edge and image and (semiconductor or wafer) and defect
S25	15	("4894540").URPN.